



NSAI
Standards

Irish Standard
I.S. EN 62132-2:2011

Integrated circuits - Measurement of
electromagnetic immunity -- Part 2:
Measurement of radiated immunity -
TEM cell and wideband TEM cell
method (IEC 62132-2:2010 (EQV))

I.S. EN 62132-2:2011

Incorporating amendments/corrigenda issued since publication:

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SWiFT xxx: A rapidly developed recommendatory document based on the consensus of the participants of an NSAI workshop.

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English version

**Integrated circuits -
Measurement of electromagnetic immunity -
Part 2: Measurement of radiated immunity -
TEM cell and wideband TEM cell method
(IEC 62132-2:2010)**

Circuits intégrés -
Mesure de l'immunité électromagnétique -
Partie 2: Mesure de l'immunité rayonnée -
Méthode de cellule TEM et cellule TEM à
large bande
(CEI 62132-2:2010)

Integrierte Schaltungen -
Messung der elektromagnetischen
Störfestigkeit -
Teil 2: Messung der Störfestigkeit bei
Einstrahlungen -
TEM-Zellen- und Breitband-TEM-
Zellenverfahren
(IEC 62132-2:2010)

This European Standard was approved by CENELEC on 2011-01-02. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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Foreword

The text of document 47A/838/FDIS, future edition 1 of IEC 62132-2, prepared by SC 47A, Integrated circuits, of IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62132-2 on 2011-01-02.

This part of EN 62132 is to be read in conjunction with EN 62132-1.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CEN and CENELEC shall not be held responsible for identifying any or all such patent rights.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2011-10-02
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2014-01-02

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 62132-2:2010 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

[7] IEC 61000-4-3:2006	NOTE Harmonized as EN 61000-4-3:2006 (not modified).
IEC 61000-4-3:2006/A1:2007	NOTE Harmonized as EN 61000-4-3:2006/A1:2008 (not modified).
[8] IEC 61000-4-6:2008	NOTE Harmonized as EN 61000-4-6:2009 (not modified).
[9] IEC 61000-4-20:2003	NOTE Harmonized as EN 61000-4-20:2003 (not modified).
[10] CISPR 16-1-1:2006	NOTE Harmonized as EN 55016-1-1:2007 (not modified).
[12] CISPR 16-1-5:2003	NOTE Harmonized as EN 55016-1-5:2004 (not modified).
[13] CISPR 16-2-1:2008	NOTE Harmonized as EN 55016-2-1:2009 (not modified).
[15] CISPR 16-2-3:2006	NOTE Harmonized as EN 55016-2-3:2006 (not modified).
[16] CISPR 16-2-4:2003	NOTE Harmonized as EN 55016-2-4:2004 (not modified).

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-131	2002	International Electrotechnical Vocabulary (IEV) - Part 131: Circuit theory	-	-
IEC 60050-161	1990	International Electrotechnical Vocabulary (IEV) - Chapter 161: Electromagnetic compatibility	-	-
IEC 61967-2	-	Integrated circuits - Measurement of electromagnetic emissions, 150 kHz to 1 GHz - Part 2: Measurement of radiated emissions - TEM cell and wideband TEM cell method	EN 61967-2	-
IEC 62132-1	2006	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 62132-1 + corr. November	2006 2006

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CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references	5
3 Terms and definitions	5
4 General	6
5 Test conditions	7
6 Test equipment.....	7
6.1 General	7
6.2 Cables.....	7
6.3 RF disturbance source	7
6.4 TEM cell.....	8
6.5 Gigahertz TEM cell.....	8
6.6 50-Ω termination	8
6.7 DUT monitor.....	8
7 Test set-up	8
7.1 General	8
7.2 Test set-up details.....	8
7.3 EMC test board	10
8 Test procedure	10
8.1 General	10
8.2 Immunity measurement	10
8.2.1 General	10
8.2.2 RF disturbance signals	10
8.2.3 Test frequencies.....	11
8.2.4 Test levels and dwell time	11
8.2.5 DUT monitoring	11
8.2.6 Detail procedure.....	11
9 Test report.....	12
Annex A (normative) Field strength characterization procedure.....	13
Annex B (informative) TEM CELL and wideband TEM cell descriptions.....	21
Bibliography.....	22
Figure 1 – TEM and GTEM cell cross-section	9
Figure 2 – TEM cell test set-up	9
Figure 3 – GTEM cell test set-up.....	10
Figure 4 – Immunity measurement procedure flowchart	12
Figure A.1 – E-field characterization test fixture.....	14
Figure A.2 – The electric field to voltage transfer function.....	16
Figure A.3 – H-field characterization test fixture.....	19
Figure A.4 – The magnetic field to voltage transfer function	20

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INTEGRATED CIRCUITS – MEASUREMENT OF
ELECTROMAGNETIC IMMUNITY –**
**Part 2: Measurement of radiated immunity –
TEM cell and wideband TEM cell method**

FOREWORD

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International Standard IEC 62132-2 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/838/FDIS	47A/843/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 62132 is to be read in conjunction with IEC 62132-1.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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